

Search Notes**Application/Control No.**

10/750,121

Examiner

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Applicant(s)/Patent under Reexamination

LIN ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	172-176, 50-52,56, 63,68,90	2/22/2005	HLN
	164		
↓	514,515	↓	
372	38.02	2/23/2005	
345	39	✓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	2/23/2005	HLN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner